1N50-KW **Preliminary Power MOSFET**

1A, 500V N-CHANNEL **POWER MOSFET**

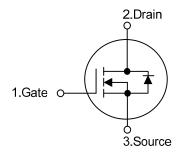
DESCRIPTION

The UTC 1N50-KW is a high voltage MOSFET and is designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and have a high rugged avalanche characteristics. This power MOSFET is usually used at high speed switching applications in power supplies, PWM motor controls, high efficient DC to DC converters and bridge circuits.

FEATURES

- * $R_{DS(ON)}$ < 10 Ω @ V_{GS} =10V, I_D =0.5A
- * Fast switching capability
- * Avalanche energy specified
- * Improved dv/dt capability, high ruggedness

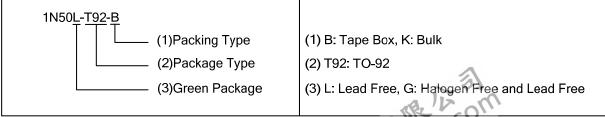




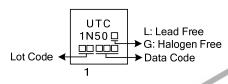
ORDERING INFORMATION

Ordering Number		Dookaga	Pin Assignment			Dooking	
Lead Free	Halogen Free	Package	1	2	3	Packing	
1N50L-T92-B	1N50G-T92-B	TO-92	G	D	S	Tape Box	
1N50L-T92-K	1N50G-T92-K	TO-92	G	D	S	Bulk	

Pin Assignment: G: Gate D: Drain S: Source



MARKING



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TO-92

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■ **ABSOLUTE MAXIMUM RATINGS** (T_C = 25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT	
Drain-Source Voltage		V_{DSS}	500	V	
Gate-Source Voltage		V_{GSS}	±30	V	
Continuous Drain Current		I _D	1	Α	
Avalanche Energy	Avalanche Energy Single Pulsed (Note 2)		50	mJ	
Peak Diode Recovery	dv/dt (Note 3)	dv/dt	4.5	V/ns	
Power Dissipation (T _A =25°C)		P_D	0.6	W	
Junction Temperature		T_J	+150	°C	
Operating Temperature	e	T _{OPR}	-55 ~ + 150	°C	
Storage Temperature		T _{STG}	-55 ~ + 150	°C	

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. L = 100mH, I_{AS} = 1A, V_{DD} = 50V, R_G = 25 Ω , Starting T_J = 25 $^{\circ}$ C
- 3. $I_{SD} \le 1.2A$, di/dt $\le 200A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^{\circ}C$

■ THERMAL DATA

PARAMETER	SYMBOL	RATINGS	UNIT	
Junction to Ambient	θ_{JA}	180	°C/W	
Junction to Case	θ_{JC}	88	°C/W	

■ **ELECTRICAL CHARACTERISTICS** (T_C = 25°C, unless otherwise specified)

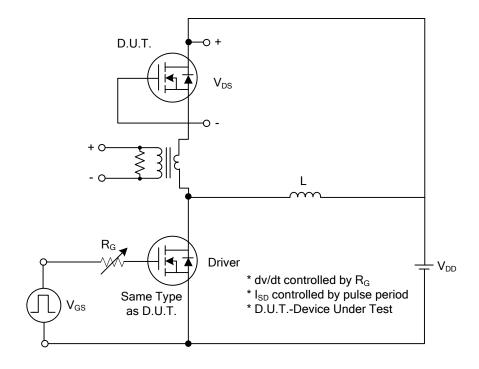
PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT			
OFF CHARACTERISTICS									
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V, I _D =250μA	500			V			
Drain-Source Leakage Current	I _{DSS}	V _{DS} =500V, V _{GS} =0V			10	μΑ			
Cata Source Leakage Current Forward	I _{GSS}	V _{GS} =30V, V _{DS} =0V			100	nA			
Gate-Source Leakage Current Reverse		V _{GS} =-30V, V _{DS} =0V			-100	nA			
Breakdown Voltage Temperature Coefficient	$\triangle BV_{DSS}/\triangle T_{J}$	I _D =250μA		0.4		V/°C			
ON CHARACTERISTICS									
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS}=V_{GS}$, $I_D=250\mu A$	3.0		5.5	V			
Static Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =0.5A		8.6	10	Ω			
DYNAMIC CHARACTERISTICS									
Input Capacitance	C _{ISS}			135		pF			
Output Capacitance	Coss	V _{DS} =25V, V _{GS} =0V, f=1MHz		17		pF			
Reverse Transfer Capacitance	C _{RSS}	1		4.7		pF			
SWITCHING CHARACTERISTICS									
Turn-On Delay Time	t _{D(ON)}			16.5		ns			
Turn-On Rise Time	t _R	V_{DD} =30V, I_D =1A, R_G =25 Ω ,		30		ns			
Turn-Off Delay Time	t _{D(OFF)}	V _{GS} =10V (Note 2,3)		23		ns			
Turn-Off Fall Time	t _F			30		ns			
Total Gate Charge	Q_G	1/ 50// 1/ 40// 1 4 24		8		nC			
Gate-Source Charge	Q_GS	V_{DS} =50V, V_{GS} =10V, I_{D} =1.3A -R _G =3.3kΩ(Note 2, 3)		2.0		nC			
Gate-Drain Charge	Q_{GD}	R _G -3.3KΩ(Note 2, 3)		1.4		nC			
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS									
Drain-Source Diode Forward Voltage	V_{SD}	V _{GS} =0V, I _S =1A	3		1.4	V			
Maximum Continuous Drain-Source Diode	Is	K PV a CO	*		1.0				
Forward Current		18 680.			1.0	Α			
Maximum Pulsed Drain-Source Diode	I _{SM}	21 PM 170			4.0	Α			
Forward Current	ISM	109 NO			7.0				

Notes: 1. Repetitive Rating: Pulse width limited by maximum junction temperature

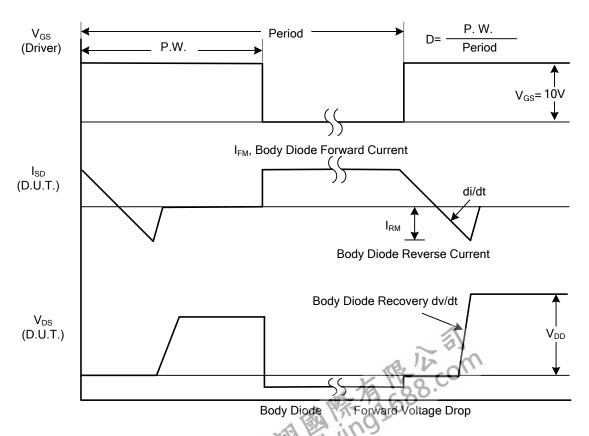
- 2. Pulse Test: Pulse Width ≤300µs, Duty Cycle≤2%
- 3. Essentially Independent of Operating Temperature



TEST CIRCUITS AND WAVEFORMS

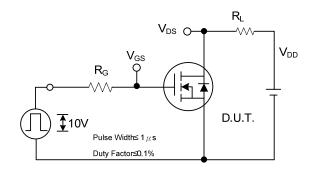


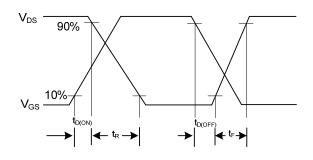
Peak Diode Recovery dv/dt Test Circuit



Peak Diode Recovery dv/dt Waveforms

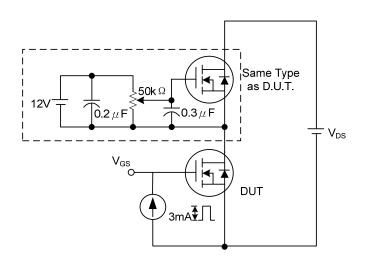
TEST CIRCUITS AND WAVEFORMS (Cont.)

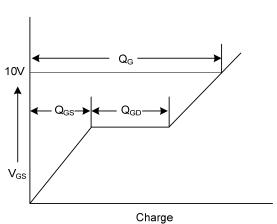




Switching Test Circuit

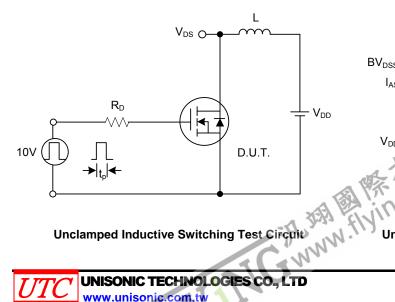
Switching Waveforms

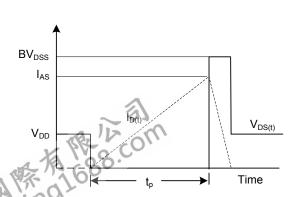




Gate Charge Test Circuit

Gate Charge Waveform





Unclamped Inductive Switching Waveforms

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